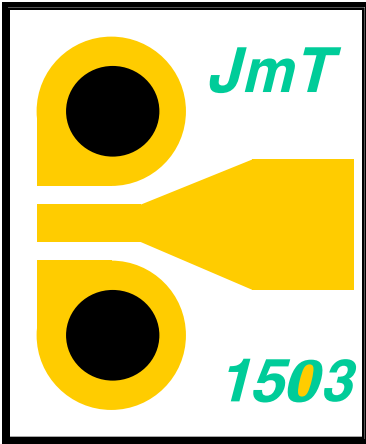


**ProbePoint™ 1503 Test Interface Circuit - Coplanar to Microstrip**



Test adapter and interface substrate for microstrip type active and passive components. Useful as a contact for test of devices which have a nominal “back-side ground.”

Zo 50Ω

Metalization

Front/Back Au  
Resistors TaN

Size 15 X 38 X 46 mils

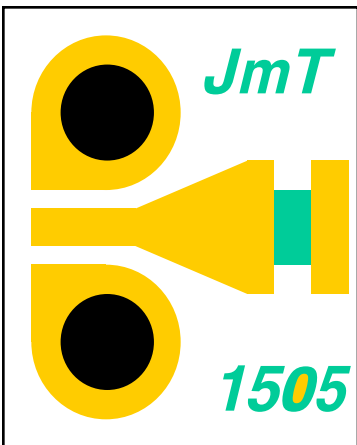
**Features**

- Compatible to coplanar probes 125μ to 450μ pitch
- Controlled impedance transition
- High quality backside vias
- Calibration Substrate available

**Benefits**

- High precision
- High repeatability
- High accuracy measurements
- Calibration structures available
- Low cost test tooling

**ProbePoint™ 1505 Test Interface Circuit - Coplanar to Microstrip with Series Resistor**



Test adapter and interface substrate for microstrip type active and passive components. Useful as a contact for test of devices which have a nominal “back-side ground.” Series resistor in signal path can be used to stabilize the bias conditions of high gain bipolar and FET devices.

Zo 50Ω

Series Resistor 25Ω ± .5Ω

Metalization

Front/Back Au  
Resistors TaN

Size 15 X 38 X 46 mils

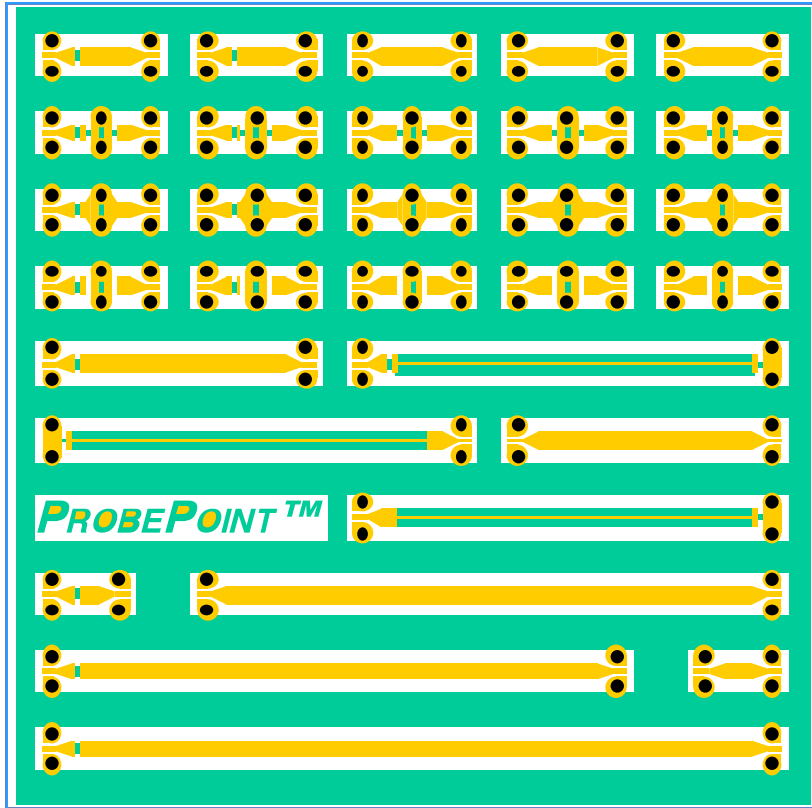
**Features**

- Compatible to coplanar probes 125μ to 450μ pitch
- Series Resistor in signal path for stable bias and precise high frequency measurements
- Controlled impedance transition
- High quality backside vias
- Calibration Substrate available

**Benefits**

- High precision
- High repeatability
- High accuracy measurements
- Calibration structures available
- Low cost test tooling

**ProbePoint™ CM15 Calibration Substrate - Coplanar to Microstrip (15 mil)**



This substrate contains calibration structures to be used in the establishment of measurement corrections terms for measurements using network and time domain analysis. A variety of microwave structures which support the popular calibration methods are available for all the ProbePoint™ 15 Test Interface Circuits. This allows direct calibration to the microstrip bond pad side of the ProbePoint™ Test Interface Structures. Calibration substrate is 'bonded' to 10 mil thick backing plate for mechanical ruggedness.

Zo	50Ω nominal
Metalization	
Front/Back	Au
Resistors	TaN
Size	25 X 630 X 630 mils

**Features**

- Compatible to coplanar probes  
    125μ to 450μ pitch
- Flexible to various calibration methods:
  - SOLT
  - LRM
  - LRL
  - TRL
- Laser trimmed resistors - ±1%
- Controlled impedance transition
- High quality backside vias
- Calibrates and corrects for Series resistance of PP™ 1505 adapter substrates.

**Benefits**

- Direct Calibration
- High repeatability
- High accuracy calibration
- Low cost
- User flexibility